1) CALL TO ORDER (Mike Seavey)
Meeting called to order at 9:12 AM

2) ANNOUNCEMENTS (Teresa Lopes)

3) INTRODUCTIONS/ATTENDANCE SHEET (All)

4) CALL FOR PATENTS (Mike Seavey)
See IEEE Patent Slides

5) 16-1 MEETING AGENDA (Mike Seavey)
Updated agenda reviewed

6) CHAIRS REPORT & SCC20’s 50TH ANNIVERSARY (Mike Seavey)
See SCC20 16-1 Chairs Report

7) NEW SCC20 COMMITTEE & WORKING GROUP WEB PAGES (Christy Bahn)
Christy Bahn showed the group a preview of the new committee and working group pages. There was a lot of discussion about what to do with the old sub-committee pages. We want to keep the old sub-committee data around. There are external links to these pages that we would like not to break. Additional feedback should be sent to Christy Bahn.

8) WORKING GROUP PLANS FOR THIS MEETING

P1445 WG– M. Seavey
Review final document. The Document basically done. Going to Steering to start Sponsor ballot

P1505.1 WG– S. Mann / R. Spinner
Review and mark up current standard. Would like a Word version of the standard from the IEEE.

P1514 WG– S. Mann / R. Spinner
Review components and get into the details – still a lot of work to be done

P1636 WG– M. Seavey / J. Sheppard
Update the previously published standard to latest template. Roll SIMICA common into the base standard. EXPRESS has been dropped. Replacing with OWL (stronger compatibility with XML).

P1636.2 WG– M. Seavey / J. Sheppard
Review candidate OWL ontology. Will eventually do the same thing for 1636.1

P1641.1a WG– C. Gorringe / I. Neag
Adding amendment for TSF libraries (guidance). Review work being done with digital buses. eCASS suite of TSF libraries to represent the ATLAS.

P1671.1 WG – A. Jain
Finalizing schema for new data flows. Review schema and examples. Finished schema for digital and serial buses. Hope to close 9 of the 11 remaining open issues. Publish schema to box.net in September

P1671.3 WG – I. Neag
One open action item. Will get closed once serial bus issues with 1671.1 get closed

P1871.2 WG – C. Gorringe / T. Winquist
Review document and get ready to go to ballot. All feedback has been incorporated

9) STUDY GROUP PLANS FOR THIS MEETING

1505 – S. Mann
Looking for feedback to figure out what to do with the standard

10) IEC TC91 WG 15 REPORT (Mike Seavey)
On May 17, the TC91 chair (Chris Hunt (UK)) approved having Mike as acting convener of the WG15 meeting.
Meeting on Thursday

11) ADJOURN TO WORKING GROUPS
Instructions for the WG Chair

The IEEE-SA strongly recommends that at each WG meeting the chair or a designee:

- Show slides #1 through #4 of this presentation

- Advise the WG attendees that:
  - The IEEE’s patent policy is described in Clause 6 of the IEEE-SA Standards Board Bylaws;
  - Early identification of patent claims which may be essential for the use of standards under development is strongly encouraged;
  - There may be Essential Patent Claims of which the IEEE is not aware. Additionally, neither the IEEE, the WG, nor the WG chair can ensure the accuracy or completeness of any assurance or whether any such assurance is, in fact, of a Patent Claim that is essential for the use of the standard under development.

- Instruct the WG Secretary to record in the minutes of the relevant WG meeting:
  - That the foregoing information was provided and that slides 1 through 4 (and this slide 0, if applicable) were shown;
  - That the chair or designee provided an opportunity for participants to identify patent claim(s)/patent application claim(s) and/or the holder of patent claim(s)/patent application claim(s) of which the participant is personally aware and that may be essential for the use of that standard
  - Any responses that were given, specifically the patent claim(s)/patent application claim(s) and/or the holder of the patent claim(s)/patent application claim(s) that were identified (if any) and by whom.

- The WG Chair shall ensure that a request is made to any identified holders of potential essential patent claim(s) to complete and submit a Letter of Assurance.
- It is recommended that the WG chair review the guidance in IEEE-SA Standards Board Operations Manual 6.3.5 and in FAQs 14 and 15 on inclusion of potential Essential Patent Claims by incorporation or by reference.

Note: WG includes Working Groups, Task Groups, and other standards-developing committees with a PAR approved by the IEEE-SA Standards Board.

(Optional to be shown)
Participants, Patents, and Duty to Inform

All participants in this meeting have certain obligations under the IEEE-SA Patent Policy.

- Participants [Note: Quoted text excerpted from IEEE-SA Standards Board Bylaws subclause 6.2]:
  - “Shall inform the IEEE (or cause the IEEE to be informed)” of the identity of each “holder of any potential Essential Patent Claims of which they are personally aware” if the claims are owned or controlled by the participant or the entity the participant is from, employed by, or otherwise represents
  - “Should inform the IEEE (or cause the IEEE to be informed)” of the identity of “any other holders of potential Essential Patent Claims” (that is, third parties that are not affiliated with the participant, with the participant’s employer, or with anyone else that the participant is from or otherwise represents)
- The above does not apply if the patent claim is already the subject of an Accepted Letter of Assurance that applies to the proposed standard(s) under consideration by this group
- Early identification of holders of potential Essential Patent Claims is strongly encouraged
- No duty to perform a patent search
**Patent Related Links**

All participants should be familiar with their obligations under the IEEE-SA Policies & Procedures for standards development.

Patent Policy is stated in these sources:

IEEE-SA Standards Boards Bylaws

http://standards.ieee.org/develop/policies/bylaws/sect6-7.html#6

IEEE-SA Standards Board Operations Manual


Material about the patent policy is available at

http://standards.ieee.org/about/sasb/patcom/materials.html

If you have questions, contact the IEEE-SA Standards Board Patent Committee Administrator at patcom@ieee.org or visit

http://standards.ieee.org/about/sasb/patcom/index.html

This slide set is available at

https://development.standards.ieee.org/myproject/Public/mytools/mob/slideset.ppt
Call for Potentially Essential Patents

If anyone in this meeting is personally aware of the holder of any patent claims that are potentially essential to implementation of the proposed standard(s) under consideration by this group and that are not already the subject of an Accepted Letter of Assurance:

- Either speak up now or
- Provide the chair of this group with the identity of the holder(s) of any and all such claims as soon as possible or
- Cause an LOA to be submitted
Other Guidelines for IEEE WG Meetings

- All IEEE-SA standards meetings shall be conducted in compliance with all applicable laws, including antitrust and competition laws.
  - Don’t discuss the interpretation, validity, or essentiality of patents/patent claims.
  - Don’t discuss specific license rates, terms, or conditions.
    - Relative costs, including licensing costs of essential patent claims, of different technical approaches may be discussed in standards development meetings.
      - Technical considerations remain primary focus
  - Don’t discuss or engage in the fixing of product prices, allocation of customers, or division of sales markets.
  - Don’t discuss the status or substance of ongoing or threatened litigation.
  - Don’t be silent if inappropriate topics are discussed … do formally object.

See IEEE-SA Standards Board Operations Manual, clause 5.3.10 and “Promoting Competition and Innovation: What You Need to Know about the IEEE Standards Association's Antitrust and Competition Policy” for more details.
Chairs Report
SCC20’s 50th Anniversary
1966-2016

- I have created a 25 page brief history of the Committee.
  - PDF and Paper Copies available.
  - Available on the “new” SCC20 web-site.

- Working with the IEEE, we have created a SCC20 Lapel Pin.

A Brief History of the first 50 years of what today is IEEE SCC20.
It’s Organizations, Meetings and the Standards it’s Developed & Maintained
— November 1966 to 2016 —

Mike Seavey
IEEE Standards Coordinating Committee 20 (SCC20) 16-1 Meeting
SCC20’s 50th Anniversary 1966-2016

- I was interviewed by the IEEE for:
  - The IEEE Standards Insight Blog. (available now)
  - The IEEE History Center Newsletter. (for the July publication)
    - The IEEE History Center is located at the Stevens Institute of Technology in Hoboken NJ.
Working Group Chair Awards

IEEE Standard for Automatic Test Markup Language (ATML) Test Adapter Description

IEEE Standards Coordinating Committee 20

Sponsored by the
IEEE Standards Coordinating Committee 20 on
Test and Diagnosis for Electronic Systems

IEEE Std 1671.5™-2015
(Revision of
IEEE Std 1671.5-2008)

IEEE Standards Coordinating Committee 20

Sponsored by the
IEEE Standards Coordinating Committee 20 on
Test and Diagnosis for Electronic Systems

IEEE Std 1671.6™-2015
(Revision of
IEEE Std 1671.5-2008)
Committee Introduction

• We are developing and/or maintaining a total of 30 active standards.

• We presently have 9 have active Project Authorization Requests (PAR)s.

• We operate under the IEEE Operating Hierarchy as well as:
  • Policies and Procedures for Standards Development for the Standards Coordinating Committee 20 (SCC20)
  • Policies and Procedures for: SCC20 Working Groups
SCC20 Organization

Active Working Groups (Revision to a Published Standard or Development of the Initial Standard)

- IEEE-P1445 DTIF
  - Revision of IEEE-1445-1998 (R2010)
  - WG Chair: Mike Seavey

- IEEE-P1505.1 Common Test Interface Pin Map Configuration
  - Revision of IEEE-1505.1-2008
  - WG Chair: Rob Spinner

- IEEE-P1514 Fixtures Applied to Generic Test Interfaces
  - New Recommended Practice
  - WG Chair: Steve Mann

- IEEE-P1636 SIMICA
  - Revision of IEEE-1636-2009
  - WG Chair: John Sheppard

- IEEE-P1636.2 SIMICA: MAI
  - Revision of IEEE-1636.2-2010
  - WG Chair: John Sheppard

- IEEE-P1641.1a Amendment to IEEE-1641.1
  - New Amendment
  - WG Chair: Ion Naeg

- IEEE-P1641.2 Intrinsic Signal Path Information
  - New Recommended Practice
  - WG Chair: Chris Gorringe

Chair: Mike Seavey
Vice Chair: Chris Gorringe
Secretary/Treasurer: Teresa Lopes

Designated Representatives
John Sheppard (CS), Joe Stanco (I&M), Joe Stanco (AES),
Bill Ross (DoD), Malcolm Brown (MoD),
Les Orlidge (NDIA)

IEEE Staff Liaison
Christy Bahn

IEC TC 91 WG 15
IEC TC 65C
IEEE Staff Liaison
Christy Bahn

Published IEEE Standards (Maintained By SCC20)

- IEEE-448.1-2003
- IEEE-448.2-1992
- IEEE-716-1995 (R2011)
- IEEE-771-1998 (R2009)
- IEEE-1155-1992
- IEEE-1174-2000
- IEEE-1232-2010
- IEEE-1232.3-2014
- IEEE-1505.3-2015
- IEEE-1546-2000 (R2011)
- IEEE-1546.1-2013
- IEEE-1636.1-2013
- IEEE-1636.99-2013
- IEEE-1641-2010
- IEEE-1641.1-2010
- IEEE-1641.1-2013
- IEEE-1671-2010
- IEEE-1671.2-2012
- IEEE-1671.4-2014
- IEEE-1671.5-2015
- IEEE-1671.6-2015
- IEEE-1871.1-2014
## SCC20 Standards Tracking

<table>
<thead>
<tr>
<th>Publication</th>
<th>Project</th>
<th>PAR by</th>
<th>PAR Approval Date</th>
<th>PAR Expiration Date</th>
<th>Valid Standard Until</th>
<th>IEC Adoption</th>
</tr>
</thead>
<tbody>
<tr>
<td>716-1995(R2011)</td>
<td>—</td>
<td>2017</td>
<td>—</td>
<td>—</td>
<td>12/31/2021</td>
<td>IEC 61926-1 Ed. 1.0 Administratively Withdraw in 2021</td>
</tr>
<tr>
<td>1232-2010</td>
<td>—</td>
<td>2016</td>
<td>—</td>
<td>—</td>
<td>12/8/2020</td>
<td>IEC 62243 Ed. 2.0</td>
</tr>
<tr>
<td>1232.3-2014</td>
<td>—</td>
<td>2020</td>
<td>—</td>
<td>—</td>
<td>12/31/2024</td>
<td></td>
</tr>
<tr>
<td>1505-2010</td>
<td>—</td>
<td>2016</td>
<td>—</td>
<td>—</td>
<td>9/30/2020</td>
<td>IEC 63004 Ed 1.0 IEC Published December 30, 2015</td>
</tr>
<tr>
<td>1505.1-2008</td>
<td>P1505.1</td>
<td>—</td>
<td>December 5, 2015</td>
<td>December 31, 2019</td>
<td>12/31/2018</td>
<td>IEC 63003 Ed 1.0 IEC Published December 30, 2015</td>
</tr>
<tr>
<td>1505.3-2015</td>
<td>—</td>
<td>2021</td>
<td>—</td>
<td>—</td>
<td>12/31/2025</td>
<td></td>
</tr>
<tr>
<td>—</td>
<td>P1514</td>
<td>—</td>
<td>December 10, 2014</td>
<td>December 31, 2018</td>
<td>—</td>
<td>Merged material with 1445, Administratively Withdraw in 2021</td>
</tr>
<tr>
<td>1546-2000(R2011)</td>
<td>—</td>
<td>2017</td>
<td>—</td>
<td>—</td>
<td>12/31/2021</td>
<td></td>
</tr>
<tr>
<td>1636-2009</td>
<td>P1636</td>
<td>—</td>
<td>December 5, 2015</td>
<td>December 31, 2019</td>
<td>12/31/2019</td>
<td>Under the IEC SMB question in principle vote for the dual logo process</td>
</tr>
<tr>
<td>1636.1-2013</td>
<td>—</td>
<td>2019</td>
<td>—</td>
<td>—</td>
<td>12/31/2023</td>
<td>Under the IEC SMB question in principle vote for the dual logo process</td>
</tr>
<tr>
<td>1636.2-2010</td>
<td>P1636.2</td>
<td>—</td>
<td>August 23, 2013</td>
<td>December 31, 2017</td>
<td>12/31/2020</td>
<td></td>
</tr>
<tr>
<td>1636.99-2013</td>
<td>—</td>
<td>2019</td>
<td>—</td>
<td>—</td>
<td>12/31/2023</td>
<td>Under the IEC SMB question in principle vote for the dual logo process</td>
</tr>
<tr>
<td>1641-2010</td>
<td>—</td>
<td>2016</td>
<td>—</td>
<td>—</td>
<td>6/17/2020</td>
<td>IEC 62529 Ed. 2.0</td>
</tr>
<tr>
<td>1641.1-2013</td>
<td>—</td>
<td>2019</td>
<td>—</td>
<td>—</td>
<td>12/31/2023</td>
<td></td>
</tr>
<tr>
<td>—</td>
<td>P1641.1a</td>
<td>—</td>
<td>December 11, 2013</td>
<td>December 31, 2017</td>
<td>—</td>
<td></td>
</tr>
<tr>
<td>1671-2010</td>
<td>—</td>
<td>2016</td>
<td>—</td>
<td>—</td>
<td>9/30/2020</td>
<td>IEC 61671 Ed 1.0</td>
</tr>
<tr>
<td>1671.1-2009</td>
<td>P1671.1</td>
<td>—</td>
<td>June 17, 2010</td>
<td>December 31, 2016</td>
<td>12/31/2019</td>
<td></td>
</tr>
<tr>
<td>1671.2-2012</td>
<td>—</td>
<td>2018</td>
<td>—</td>
<td>—</td>
<td>12/31/2022</td>
<td>IEC 61671-2 Ed 1.0 IEC Published April 8, 2016</td>
</tr>
<tr>
<td>1671.3-2007</td>
<td>P1671.3</td>
<td>—</td>
<td>June 17, 2010</td>
<td>December 31, 2016</td>
<td>12/31/2018</td>
<td></td>
</tr>
<tr>
<td>1671.4-2014</td>
<td>—</td>
<td>2020</td>
<td>—</td>
<td>—</td>
<td>12/31/2024</td>
<td>IEC 61671-4 Ed 1.0 IEC Published April 8, 2016</td>
</tr>
<tr>
<td>1671.5-2015</td>
<td>—</td>
<td>2021</td>
<td>—</td>
<td>—</td>
<td>12/31/2025</td>
<td>IEC 61671-5 Ed 1.0 IEC Published April 8, 2016</td>
</tr>
<tr>
<td>1671.6-2015</td>
<td>—</td>
<td>2021</td>
<td>—</td>
<td>—</td>
<td>12/31/2025</td>
<td>IEC 61671-6 Ed 1.0 IEC Published April 8, 2016</td>
</tr>
<tr>
<td>1871.1-2014</td>
<td>—</td>
<td>2014</td>
<td>—</td>
<td>—</td>
<td>12/31/2024</td>
<td></td>
</tr>
<tr>
<td>—</td>
<td>P1871.2</td>
<td>—</td>
<td>June 16, 2011</td>
<td>December 31, 2017</td>
<td>—</td>
<td></td>
</tr>
</tbody>
</table>

As of 5/19/2016

<table>
<thead>
<tr>
<th>Discuss</th>
<th>In Publication</th>
<th>PAR due to expire</th>
<th>In ballot</th>
<th>IEC TC91 WG 15 Design Automation: Testing of Electrotechnical Products</th>
</tr>
</thead>
<tbody>
<tr>
<td>Std. inactive before the PAR expires</td>
<td>IEC TC65C Industrial Networks</td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>
# SASB Meeting Deadlines & Schedules 2016

<table>
<thead>
<tr>
<th>Deadline for Submission</th>
<th>Meeting</th>
</tr>
</thead>
<tbody>
<tr>
<td>December 9, 2015 √</td>
<td>January 19: NesCom/RevCom telecon √</td>
</tr>
<tr>
<td>January 22, 2016 √</td>
<td>March 1-3: New Delhi India √</td>
</tr>
<tr>
<td>March 22, 2016 √</td>
<td>May 2: NesCom/RevCom telecon √</td>
</tr>
<tr>
<td>May 20, 2016 √</td>
<td>June 28-30: Berlin Germany</td>
</tr>
<tr>
<td>August 5, 2016</td>
<td>September 16: NesCom/RevCom telecon</td>
</tr>
<tr>
<td></td>
<td>September 22: SASB telecon</td>
</tr>
<tr>
<td>October 17, 2016</td>
<td>December 5-7: Piscataway NJ</td>
</tr>
</tbody>
</table>

√ = Meeting or deadline has occurred
### SASB Meeting Deadlines & Schedules 2017

<table>
<thead>
<tr>
<th>Deadline for Submission</th>
<th>Meeting</th>
</tr>
</thead>
<tbody>
<tr>
<td>December 20, 2016</td>
<td>January 30: NesCom/RevCom telecon</td>
</tr>
<tr>
<td>February 10, 2017</td>
<td>March 21-23: Shenzhen China</td>
</tr>
<tr>
<td>March 24, 2017</td>
<td>May 4: NesCom/RevCom telecon</td>
</tr>
<tr>
<td>May 5, 2017</td>
<td>June 13-15: Milan Italy</td>
</tr>
<tr>
<td>July 28, 2017</td>
<td>September 7: NesCom/RevCom telecon</td>
</tr>
<tr>
<td></td>
<td>September 28: SASB telecon</td>
</tr>
<tr>
<td>October 16, 2017</td>
<td>December 4-6: Piscataway NJ</td>
</tr>
</tbody>
</table>
Committee Quorum Numbers

• **“Steering”** (12 voting members)
  ➢ 6

  Mike Seavey, Chris Gorringe, Teresa Lopes, John Sheppard, Joe Stanco, Bill Ross, Malcolm Brown, Les Orlidge, Steve Mann, Rob Spinner, Ion Naeg, Anand Jain
# Working Group Quorum

## Sponsor Committees

<table>
<thead>
<tr>
<th>Name</th>
<th>Designator</th>
<th>Contact</th>
<th>Staff Liaison</th>
<th>Roster</th>
<th>Actions</th>
</tr>
</thead>
<tbody>
<tr>
<td>SCC20 - Test and Diagnosis for Electronic Systems</td>
<td>SASB/SCC20</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>135</td>
<td>manage</td>
</tr>
</tbody>
</table>

## Working Group Committees

<table>
<thead>
<tr>
<th>Name</th>
<th>Designator</th>
<th>Contact</th>
<th>Staff Liaison</th>
<th>Roster</th>
<th>Actions</th>
</tr>
</thead>
<tbody>
<tr>
<td>Diagnostic and Maintenance Control Working Group</td>
<td>SASB/SCC20/DMC_WG</td>
<td>John Sheppard</td>
<td>Christy Bahn</td>
<td>44</td>
<td>manage</td>
</tr>
<tr>
<td>Hardware Interfaces Working Group</td>
<td>SASB/SCC20/HI_WG</td>
<td>Stephen Mann</td>
<td>Christy Bahn</td>
<td>47</td>
<td>manage</td>
</tr>
<tr>
<td>p1505.1 CTI Physical Pin Map Configuration Utilizing 1505 Std</td>
<td>SASB/SCC20/p1505.1</td>
<td>Robert Spinner</td>
<td>Christy Bahn</td>
<td>5</td>
<td>manage</td>
</tr>
<tr>
<td>1871.2 WG</td>
<td>SASB/SCC20/P1871.2</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>4</td>
<td>manage</td>
</tr>
<tr>
<td>Test and ATS Description Working Group</td>
<td>SASB/SCC20/TAD_WG</td>
<td>Ion Neag</td>
<td>Christy Bahn</td>
<td>46</td>
<td>manage</td>
</tr>
<tr>
<td>Test Information Integration Working Group</td>
<td>SASB/SCC20/TII_WG</td>
<td>Chris Gorringe</td>
<td>Christy Bahn</td>
<td>61</td>
<td>manage</td>
</tr>
</tbody>
</table>

## Projects
<table>
<thead>
<tr>
<th>Standard Description</th>
<th>SASB/SCC20/1155</th>
<th>Mike Seavey</th>
<th>Christy Bahn</th>
<th>10 manage</th>
</tr>
</thead>
<tbody>
<tr>
<td>IEEE Standard for VMEbus Extensions for Instrumentation: VXIbus</td>
<td>SASB/SCC20/1174</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>64 manage</td>
</tr>
<tr>
<td>IEEE Standard Serial Interface for Programmable Instrumentation</td>
<td>SASB/SCC20/1871.2</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>12 manage</td>
</tr>
<tr>
<td>Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adaptors and Test Equipment</td>
<td>SASB/SCC20/488.1</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>67 manage</td>
</tr>
<tr>
<td>IEC 62243 Ed. 1 (IEEE Std 1232(TM)-2002): Standard for Artificial Intelligence Exchange and Service Tie to All Test Environments (AI-ESTATE)</td>
<td>SASB/SCC20/62529</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>6 manage</td>
</tr>
<tr>
<td>IEC 62529 Ed. 1 Standard for Signal and Test Definition</td>
<td>SASB/SCC20/DMC_WG/1232</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>49 manage</td>
</tr>
<tr>
<td>IEEE Standard for Artificial Intelligence Exchange and Service Tie to All Test Environments (AI-ESTATE)</td>
<td>SASB/SCC20/DMC_WG/1232.3</td>
<td>Simon Jessop</td>
<td>Christy Bahn</td>
<td>32 manage</td>
</tr>
<tr>
<td>IEEE Guide for the Use of Artificial Intelligence Exchange and Service Tie to All Test Environments (AI-ESTATE)</td>
<td>SASB/SCC20/DMC_WG/P1445</td>
<td>Mike Seavey</td>
<td>Christy Bahn</td>
<td>42 manage</td>
</tr>
<tr>
<td>Standard for Digital Test Interchange Format (DTIF)</td>
<td></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>
Working Group Quorum

IEEE Guide for Digital Test Interchange Format (DTIF) Application
SASB/SCC20/DMC_WG/1546
Mike Seavey
Christy Bahn
43 manage

Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA)
SASB/SCC20/DMC_WG/P1636
John Sheppard
Christy Bahn
19 manage

IEEE Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA): Exchanging Test Results and Session Information via the eXtensible Markup Language (XML)
SASB/SCC20/DMC_WG/1636.1
Mike Seavey
Christy Bahn
52 manage

SASB/SCC20/DMC_WG/1636.2
John Sheppard
Christy Bahn
60 manage

SASB/SCC20/DMC_WG/1636.99
Mike Seavey
Christy Bahn
47 manage

IEEE Standard for Receiver Fixture Interface
SASB/SCC20/HI_WG/1505
David Droste
Christy Bahn
48 manage

IEEE Standard for the Common Test Interface Pin Map Configuration for High-Density, Single-Tier Electronics Test Requirements Utilizing IEEE Std 1505
SASB/SCC20/HI_WG/1505.1
Stephen Mann
Christy Bahn
43 manage

IEEE Standard for the Universal Test Interface Framework and Pin Configuration for Portable/Benchtop Test Requirements Utilizing IEEE 1505(TM) Receiver Fixture Interface Standard
SASB/SCC20/HI_WG/1505.3
Stephen Mann
Christy Bahn
27 manage

Recommended Practice for the Design and Integration of Fixtures Applied to Generic Test Interfaces of Automatic Test Systems
SASB/SCC20/HI_WG/P1514
Stephen Mann
Christy Bahn
8 manage

Standard for the Common Test Interface Pin Map Configuration for High-Density, Single-Tier Electronics Test Requirements Utilizing IEEE Std 1505
SASB/SCC20/p1505.1/P1505.1
Robert Spinner
Christy Bahn
2 manage

Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adaptors and Test Equipment
SASB/SCC20/P1871.2/P1871.2
Mike Seavey
Christy Bahn
4 manage

IEEE Standard for Signal and Test Definition
SASB/SCC20/TAD_WG/1641
Chris Gorringe
Christy Bahn
60 manage
### Working Group Quorum

<table>
<thead>
<tr>
<th>Standard Description</th>
<th>Working Group</th>
<th>Manager</th>
<th>Vote</th>
</tr>
</thead>
<tbody>
<tr>
<td>Guide for the Use of IEEE Std 1641, IEEE Standard for Signal and Test Definition Amendment to add Guidelines for producing reusable Test Signal Frameworks (TSFs) for use on platforms utilizing Automatic Test Markup Language (ATML)</td>
<td><em>SASB/SCC20/TAD_WG/P1641.1a</em></td>
<td>Iom Neag</td>
<td>9</td>
</tr>
<tr>
<td>Standard for Automatic Test Markup Language (ATML) Test Description</td>
<td><em>SASB/SCC20/TAD_WG/P1671.1</em></td>
<td>Anand Jain</td>
<td>60</td>
</tr>
<tr>
<td>Standard for Automatic Test Markup Language (ATML) Unit Under Test (UUT) Description</td>
<td><em>SASB/SCC20/TAD_WG/P1671.3</em></td>
<td>Iom Neag</td>
<td>66</td>
</tr>
<tr>
<td>IEEE Standard Test Language for All Systems - Common/Abbreviated Test Language for All Systems (C/ATLAS)</td>
<td><em>SASB/SCC20/TAD_WG/716</em></td>
<td>Mike Seavey</td>
<td>43</td>
</tr>
<tr>
<td>IEEE Guide to the Use of the ATLAS Specification</td>
<td><em>SASB/SCC20/TAD_WG/771</em></td>
<td>Mike Seavey</td>
<td>41</td>
</tr>
<tr>
<td>IEEE Standard for Automatic Test Markup Language (ATML) for Exchanging Automatic Test Equipment and Test Information via XML</td>
<td><em>SASB/SCC20/TII_WG/1671</em></td>
<td>Mike Seavey</td>
<td>51</td>
</tr>
<tr>
<td>IEEE Standard for Automatic Test Markup Language (ATML) Instrument Description</td>
<td><em>SASB/SCC20/TII_WG/1671.2</em></td>
<td>Chris Gorringe</td>
<td>40</td>
</tr>
<tr>
<td>IEEE Standard for Automatic Test Markup Language (ATML) Test Configuration</td>
<td><em>SASB/SCC20/TII_WG/1671.4</em></td>
<td>Mike Seavey</td>
<td>70</td>
</tr>
<tr>
<td>IEEE Standard for Automatic Test Markup Language (ATML) Test Adapter Description</td>
<td><em>SASB/SCC20/TII_WG/1671.5</em></td>
<td>Chris Gorringe</td>
<td>50</td>
</tr>
<tr>
<td>IEEE Standard for Automatic Test Markup Language (ATML) Test Station Description</td>
<td><em>SASB/SCC20/TII_WG/1671.6</em></td>
<td>Chris Gorringe</td>
<td>50</td>
</tr>
<tr>
<td>IEEE Recommended Practice for Using IEEE 1671.2(TM) Instrument Description Templates for Describing Synthetic Instrumentation for Classes of Instruments such as Waveform Generators, Digitizers, External Oscillators, and Up and Down Converters</td>
<td><em>SASB/SCC20/TII_WG/1871.1</em></td>
<td>Mike Seavey</td>
<td>28</td>
</tr>
</tbody>
</table>
SCC20 Activity since the 15-2 Meeting

- SCC20 Financial Report
  - Submitted in January
- SCC20 Annual Report
  - Created and Submitted to the SASB in January
    - SASB approved the report on March 3
      - Reporting IEEE Society Membership
      - P1671.1 & P1671.3 Extension #2
- New SCC20 web-page collaboration with Christy
  - Includes Working Groups/The Old Subcommittees
- Collaboration with IEC TC91 WG 15
SCC20 Activity since the 15-2 Meeting

- A SCC20 Flyer was created to promote the committee and encourage participation.
  - 5 ½ X 8 inches
  - Copies are available
- Similar Flyers for ATML, SIMICA, AI-ESTATE and RFI are in work.
SCC20 Activity since the 15-2 Meeting

- IEEE Infographics
SCC20 Activity since the 15-2 Meeting

- SCC20 Infographic
  - Conceptual Drawing Developed
  - 50th Anniversary material has taken precedence.
Reminders:

• PAR wording does not require “Steering” approval.
  • Is the PAR within SCC20’s Scope?
  • Are resources to do the work available?

• Initiating a Sponsor Ballot requires that the Working Group receive “Steering” approval.
  • Majority approval vote

• Public Review of Standards in Sponsor Ballot.

Started July 6, 2015
IEEE Std 1445-1998

- A copy of IEEE 1445 in honor of Brit Frank is available for anyone to sign if you wish.
Questions ?